

**PREBID CLARIFICATION**

**I-HUB QUANTUM TECHNOLOGY FOUNDATION, IISER, PUNE**

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Tender Ref. No: **I-HUBQTF/PUR/24-25/011**

Tender Published Date: **06/07/2024**

Tender ID: **GEM/2024/B/5133395**

Pre-bid Conference Date: **16/07/2024, 15:00**

Item of Procurement: **Cryogenic Physical Property Measurement System**

Clarification Date: **18/07/2024**

Pre-Bid meeting was scheduled on **16/07/2024 at 3.00 PM** and minutes of meeting is as follows:

At the outset, the Technical Committee welcomed all the Members and the Representatives of Prospective Bidders and briefed in general the scope of the tender and thereafter requested the committee members to brief the bidders on the salient features of the tender.

The representatives present were satisfied with the replies given and it was informed that the corrections / additions / clarifications given, as discussed during the Pre-Bid Conference would be hosted on the website of I-HUB QTF, IISER Pune and all the Prospective Bidders are required to take cognizance of the proceedings of the Pre-Bid Conference before submitting their bids as stipulated in the Bidding Documents. Attached are the detailed technical and commercial queries with their clarifications (Annexure I).

The other terms & conditions of the notice issued on e-Procurement/GeM portal and on I-HUB QTF's website will remain unchanged. No more correspondence in this regard will be entertained. The meeting ended with vote of thanks.

Sd/-

**Project Director**

**Technical Clarifications/Amendment**

**(Annexure I)**

**TECHNICAL QUERIES**

SN	Query / Clarification Sought	Clarification / Amendment
<b>Refer GeM Tendered Specifications, Page 03, Point 3b: AC Resistance Module</b>		
1	<p>Please clarify:</p> <p>In the technical specifications, it states that the sample should use an in-plane LCC20 probe end. However, point 3a mentions a combined DC resistivity/Hall effect multi-sample scanning and switching option.</p> <p>Could you please confirm the requirements for the DC measurements? Specifically, would the LCC20 probe be preferred, or should we use an out-of-plane or in-plane probe?</p> <p>For the out-of-plane orientation: We offer either a probe with two orthogonal 8-pin sample platforms or a demountable out-of-plane LCC20 probe end.</p> <p>For the in-plane orientation: We can propose an additional CLCC20 sample in-plane probe end, which would be interchangeable with the out-of-plane probe end.</p>	<p>For DC resistivity / Hall out of plane probe can be quoted. If axis-rotation option is there, it should be quoted separately.</p>

**COMMERCIAL QUERIES**

SN	Query / Clarification Sought	Clarification / Amendment
1	Nil	Nil